

The Maximum Rejection Classifier for Pattern Detection

With

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• **Pattern Detection**: Given a pattern that is subjected to a particular type of variation, detect occurrences of this pattern in an image.

- Detection should be:
 - Accurate (small number of mis-detections/falsealarms).
 - As fast as possible.



Face detection in images



Face Examples



Variations in Faces

Faces may vary in their appearance:

- Scale
- Location
- Illumination condition
- Pose
- Identity
- Facial expression

An input Image



Compose a pyramid with 1:f resolution ratio (f=1.2)





Extract blocks

from each

location in each

resolution layer

Detected Face Positions



Face Finder

• The above type of algorithm is capable of finding faces:

- In various scales
- In various locations
- In various illumination conditions
- In various pose
- Of various identities
- In various facial expressions



Trained Classifier

Complexity

Searching for faces in a 1000x1000 image, the classifier is applied 1e6 times





The algorithm' complexity is dominated by the classifier

Pattern Detection as a Classification Problem

- Pattern detection requires a separation between two classes:
 - a. The Target class.
 - b. The Clutter class.
- Given an input pattern <u>Z</u>, we would like to classify it as Target or Clutter.



• A classifier is a non-linear parametric function $C(\underline{Z},\underline{\theta})$ of the form:

$$C(Z,\theta): \mathfrak{R}^n \to \{+1,-1\}$$

• <u>A simple example</u>: For blocks of 4 pixels $[z_1, z_2, z_3, z_4]$ we can define C{Z} as:

 $C(Z,\theta) = \operatorname{sign}(\theta_0 + \theta_1 z_1 + \theta_2 z_2 + \theta_3 z_3 + \theta_4 z_4)$



$C(\underline{Z})$ draws a separating manifold between the two classes



Supervised Learning:

• In order to obtain a precise classifier we must find a good choice of parameters $\underline{\theta}$:



Use examples with known labeling to find a good set of parameters

Example Based Classifiers

• Given two training sets:

$$\{\underline{X}_k\}_{k=1}^{N_X} \in \mathbf{X} \qquad \{\underline{Y}_k\}_{k=1}^{N_Y} \in Y$$

- We want to find a set of parameters $\underline{\theta}$ such that: $C\{X_k, \theta\} = +1$ $C\{Y_k, \theta\} = -1$
- We "hope" that the generalization is correct.

- The *Linear Classifiers* are the simplest ones.
- The decision is based on the projection of an input signal \underline{Z} onto a kernel $\underline{\theta}$.

$$C(\underline{Z},\underline{\theta}) = sign\left\{\underline{Z}^{\mathsf{T}}\underline{\theta} - \theta_{0}\right\}$$

• The parameters $\{\underline{\theta}, \theta_0\}$ define a separating hyperplane.



Designing Optimal Linear Classifiers



The Fisher Linear Classifiers

• Choose the projection kernel $\underline{\theta}$ that maximizes the Mahalanobis-distance between $X^T \underline{\theta}$ and $Y^T \underline{\theta}$

$$d_{M}(i,j) = \frac{\left\|\mu_{i} - \mu_{j}\right\|^{2}}{\sigma_{i}^{2} + \sigma_{j}^{2}}$$



maximize minimize

The Support Vector Machine (SVM)

Choose the projection kernel $\underline{\theta}$ that maximizes the classes margin d_{\min} . (Vapnik-Chernoveskis 82)



The Support Vector Machine - Continue

- The support vectors are those examples realizing the minimal distance. The decision function is composed of a linear combination of these vectors.
- The optimal projection that emerges turns out to be the solution of a QP problem.
- Generalization error is bounded, and the SVM acheives the tightest bound.

The Limitations of Linear Classifiers

- The above classifiers are suitable for linearly seperable classes (or close to this).
- In other cases:



– Map into higher dimensional feature space.

Complicated !!

Face Detection - Previous Works

- Rowley & Kanade (98), Juel & March (96): Neural Network approach - Non linear classifier.
- Sung & Poggio (98):

Clustering the faces/non-faces into sub-groups, and RBF classifier- Non Linear.

• Osuna, Freund, & Girosi (97):

Support Vector Machine - Classification in high dimensional feature space.

• Keren & Gotsman (98):

Anti-Faces method - finding a linear kernel that is orthogonal to faces and smooth.

Our Approach - Two Steps Back

• Observations:

- A typical configuration in Pattern Detection is that the Target class is surrounded by the Clutter class.
- P{Target}<<P{Clutter}</pre>



• Conclusions:

- A pdf separation is not appropriate.
- Clutter labeling should be performed fast.

Distance Definition:

• Define a distance of a point x from a pdf $p_{Y}(y)$:

$$D(x,p_Y) = \int_{y} \frac{(x-y)^2 p_Y(y)}{\sigma_y^2} dy = \frac{(x-\mu_Y)^2 + \sigma_Y^2}{\sigma_Y^2}$$

• Consequally, we define the distance of $p_X(x)$ from $p_Y(y)$:

$$D(p_{X},p_{Y}) = \int_{x} \frac{(x-\mu_{Y})^{2} + \sigma_{Y}^{2}}{\sigma_{Y}^{2}} p_{X}(x) dx = \frac{(\mu_{X}-\mu_{Y})^{2} + \sigma_{X}^{2} + \sigma_{Y}^{2}}{\sigma_{Y}^{2}}$$

$$D(p_X, p_Y) = \frac{(\mu_X - \mu_Y)^2 + \sigma_X^2 + \sigma_Y^2}{\sigma_Y^2}$$

• Alternatively, we can define the proximity of p_x to p_y :

$$\operatorname{Prox}(p_{X},p_{Y}) = \frac{\sigma_{Y}^{2}}{(\mu_{X} - \mu_{Y})^{2} + \sigma_{X}^{2} + \sigma_{Y}^{2}}$$

• Note, that the distance is asymmetric.



 $D(p_X,p_Y) < D(p_Y,p_X)$:

Optimal Classifier for Pattern Detection

• We would like to find a projection kernel $\underline{\theta}$ which minimizes the overlap between $p_x = p(X^T \underline{\theta})$ and $p_y = p(Y^T \underline{\theta})$:

$$E(\underline{\theta}) = P(X) \frac{\sigma_y^2}{(\mu_x - \mu_y)^2 + \sigma_x^2 + \sigma_y^2} + P(Y) \frac{\sigma_x^2}{(\mu_x - \mu_y)^2 + \sigma_x^2 + \sigma_y^2}$$

- If P(X)=P(Y) we obtain the Fisher Linear Classifier.
- In Pattern Detection P(X)<<P(Y), hence we get:

$$\underline{\theta} = argmin \frac{\sigma_x^2}{\left(\mu_x - \mu_y\right)^2 + \sigma_x^2 + \sigma_y^2}$$

$$\underline{\theta} = \operatorname{argmin} \frac{\sigma_x^2}{\left(\mu_x - \mu_y\right)^2 + \sigma_x^2 + \sigma_y^2}$$

The penalty term can be minimized by two alternatives:
Maximize the "between class" distance.

– Minimize σ_x while maximizing σ_y .

• The second alternative is more common in Pattern Detection.

Minimize Maximize

Maximal Rejection

- The optimal $\underline{\theta}$ assures that most $Z \in Y$ are distant from X.
- **Rejection**: two decision levels $[d_1, d_2]$ such that the number of rejected clutters is maximized while finding all targets.



Successive Rejection

- Following the first rejection as many as possible clutters were classified, while targets remain unclassified.
- In order to further reject clutter, we apply the maximal rejection technique to the remaining classes.



Formal Derivation

- In practice we have only samples from P_X and P_Y .
- The class means are estimated:

$$M_{x} = \frac{1}{L_{x}} \sum_{k} X_{k} \qquad M_{y} = \frac{1}{L_{y}} \sum_{k} Y_{k}$$

• The class covariances are estimated:

$$S_X^2 = \frac{1}{L_x} \sum_k (X_k - M_x) (X_k - M_x)^T$$
 $S_Y^2 = \frac{1}{L_Y} \sum_k (Y_k - M_Y) (Y_k - M_Y)^T$

• The means and variances after projection onto $\underline{\theta}$ are: $\mu_{x} = \underline{\theta}^{\mathsf{T}} \mathsf{M}_{x}$ and $\mu_{Y} = \underline{\theta}^{\mathsf{T}} \mathsf{M}_{Y}$ $\sigma_{x}^{2} = \theta^{\mathsf{T}} \mathsf{M}_{x} \theta$ and $\sigma_{Y}^{2} = \theta^{\mathsf{T}} \mathsf{M}_{Y} \theta$

Formal Derivation - Cont.

• The optimal $\underline{\theta}$ minimizes the following term:

$$\mathsf{E}(\underline{\theta}) = \frac{\sigma_x^2}{(\mu_x - \mu_y)^2 + \sigma_x^2 + \sigma_y^2} =$$

$$= \frac{\underline{\theta}^{\mathsf{T}} S_{\mathsf{x}} \underline{\theta}}{\underline{\theta}^{\mathsf{T}} [(\mathsf{M}_{\mathsf{Y}} - \mathsf{M}_{\mathsf{X}})(\mathsf{M}_{\mathsf{Y}} - \mathsf{M}_{\mathsf{X}})^{\mathsf{T}} + S_{\mathsf{x}} + S_{\mathsf{Y}}] \underline{\theta}} = \frac{\underline{\theta}^{\mathsf{T}} A \underline{\theta}}{\underline{\theta}^{\mathsf{T}} B \underline{\theta}}$$

• This term can be rewritten as a generalized eigenvalue problem:

 $A\underline{\theta} = \lambda B\underline{\theta}$

• The solution is the eigenvector corresponding to the smallest eigenvalue.

Proposed Algorithm

- There are two phases to the algorithm:
 - Training: Compute the projection kernels, and their thresholds. This process is performed ONCE and off line.
 - Testing: Given an image, find targets using the above found kernels and thresholds.









Limitations

- The discriminated zone is a parallelogram polytope. Thus, if the target set is non-convex, zero false alarm discrimination is impossible!!
- Even if the target-set is convex, convergence to zero false-alarms is not guaranteed.



Face Detection Results

- Kernels for finding *faces* (15x15) and *eyes* (7x15).
- Searching for eyes and faces sequentially very efficient!
- Face DB: 204 images of 40 people (ORL-DB). Each image is also rotated ±5° and vertically flipped. This produced 1224 Face images.
- Non-Face DB: 54 images All the possible positions in all resolution layers and vertically flipped about 40E6 non-face images.





Out of 44 faces, 10 faces are undetected, and 1 false alarm (the undetected faces are circled - they are either rotated or shadowed)

Results



All faces detected with no false alarms





All faces detected with 1 false alarm(looking closer, this false alarm can be considered as a face)



- For a set of 15 kernels (with appropriate decision levels), the first kernel typically removes about 90% of the pixels from further consideration. Other kernels give typically a rejection factor of 50%.
- Thus, the algorithm requires slightly more that one convolution of the image with a kernel (per each resolution layer).
- The algorithm gives very good results (probability of detection and false alarm rate) for the tests we did on frontal faces in images.

Relation to Anti-Faces (Keren & Gotsman 98)

- Projection kernels are in Null(X) and smooth.
- This can be seen as a case where the pdf of the Clutter class is defined parametrically

$$P_Y(Z) \approx e^{-Z^T (D^T D) Z}$$

where D is a derivative operator.

- In this case $S_Y = (D^T D)^{-1}$, where in the Fourier basis $(D^T D)^{-1} \Rightarrow diag(1, 1/2^2, 1/3^2, ...)$
- If $M_x \approx M_y$, minimizing the following term tends to give $\underline{\theta} \in \text{Null}(S_x)$, and smooth:

$$E(\underline{\theta}) = \frac{\underline{\theta}^T S_x \underline{\theta}}{\underline{\theta}^T \left[(M_Y - M_X) (M_Y - M_X)^T + S_x + S_Y \right] \underline{\theta}}$$

Conclusions

- MRC: projection onto pre-trained kernels, and thresholding. The process is a rejection based classification.
- Appropriate for pattern detection where pdf separation is impossible.
- Exploits the fact that P(clutter)>>P(target)
- Gives a very fast clutter labeling at the expense of slow target labeling.
- Can also deal with non linearly separable classes (convexly separable).
- Simple to apply (linear), with promising results for facedetection in images.
- A generalization of the Fisher Linear Classifier.

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